



# 제25회 한국반도체학술대회

The 25<sup>th</sup> Korean Conference on Semiconductors

2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

2018년 2월 7일(수), 09:00-10:30

Room G (봉래II+III, 6층)

## G. Device & Process Modeling, Simulation and Reliability 분과

### [WG1-G] Advanced Devices II - Simulation and Reliability

WG1-G-1 09:00-09:15	<b>RF 소자의 고 신뢰성 확보를 위한 RF인가 가속수명 시스템 설계</b> Yunho Kang, Sungsoo Chung, Sanga Kim, and Namho Kim <i>QRT Incorporated</i>
WG1-G-2 09:15-09:30	<b>New Frequency-Dependent Modeling for Intrinsic Output Admittance of HR PD-SOI MOSFETs</b> Changjo Lee and Seonghearn Lee <i>Department of Electronics Engineering, Hankuk University</i>
WG1-G-3 09:30-09:45	<b>Mobility Calculation for GaN based Heterostructure: Effects of Variational Wave Function and Screening</b> Suhyeong Cha and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, GIST</i>
WG1-G-4 09:45-10:00	<b>Characterization of Recombination Lifetime through Above-Bandgap Optical Transfer Curve in InGaAs MOSFETs</b> Junyeap Kim, Heesung Lee, Jaewon Kim, Seong Kwang Kim, Han Bin Yoo, Jaewon Park, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim <i>School of Electrical Engineering, Kookmin University</i>
WF3-F-6 14:30-14:45	<b>Simulation Study on the Effect of Unconformal Work-Function Metal Deposition on the Electrical Characteristic of Stacked-GAA MOSFET</b> Sihyun Kim <sup>1</sup> , Suhyeon Kim <sup>1</sup> , Sangwan Kim <sup>2</sup> , Euyhwan Park <sup>1</sup> , Junil Lee <sup>1</sup> , Ryoongbin Lee <sup>1</sup> , Soyeon Kim <sup>1</sup> , Hyun-Min Kim <sup>1</sup> , Kitae Lee <sup>1</sup> , Jong-Ho Lee <sup>1</sup> , and Byung-Gook <sup>1</sup> <i><sup>1</sup>ISRC and Department of Electrical and Computer Engineering, Seoul National University, <sup>2</sup>Department of Electrical and Computer Engineering, Ajou University</i>
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